







# **2009 AIG Portable XRF Workshop**QAQC and Data Management of PXRF Data







## What You Need to Remember



By using a Portable XRF Device to collect assay data,

#### YOU ARE NOW THE LABORATORY!!!

- So, you need to act like an analytical laboratory:
  - Chemistry results are only from what the X Rays see. Sampling statistics need to be taken into account e.g. homogeneity, particle size, surface effects and XRF window size!
  - Use blanks
  - Deal with matrix effects Use LAB data to verify chemistry and correct via calibration
  - use Matrix Matched certified standards to correct factors if the matrix is consistent.
  - Watch your detection limits: Longer Tests = better precision within limits

## **Also... Adding Value to Your XRF Data**



#### How can I add value to my XRF Data?

- XRF Sampling is NO Different to any other sampling regime you adopt!... Remember the Data is very valuable (& costly)!
- So, Use good QA/QC Protocols & Data Validation
- Incorporate Standards, Blanks, Field Duplicates and Check Samples to increase your understanding & confidence
- Rank & Store the Data in a well ordered & structured DB
- Remember that for ASX/TSX Reporting you must abide by JORC Code / TSX 43-101 – All about Transparency & Disclosure – so ensure your data is reported correctly!

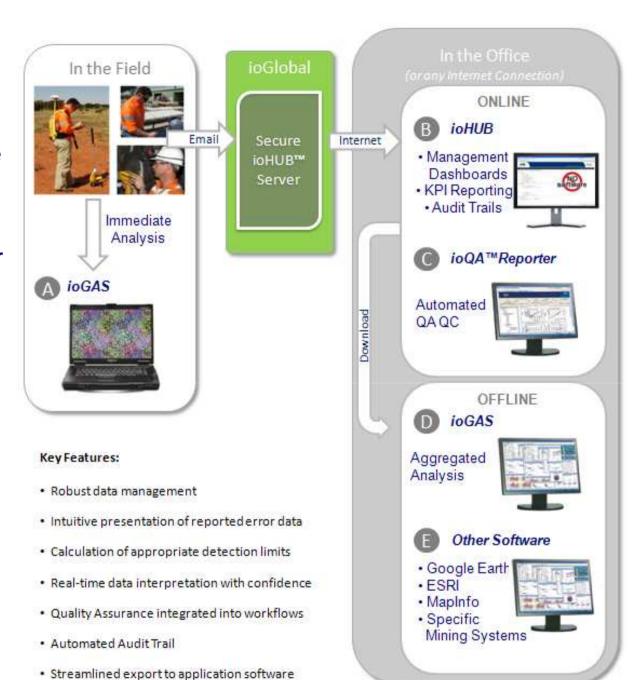


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# REPORTING, DATA SYSTEMS INTEGRATION

Integrated
Collection, Data
Management
and QAQC –
Innov-X Example

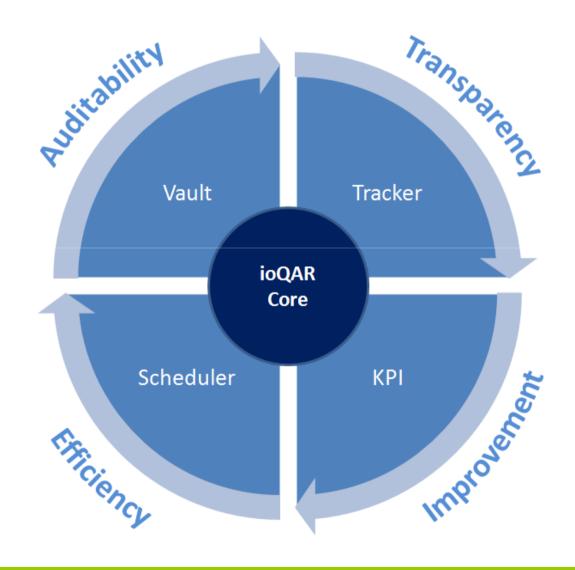
- ioGAS
- ioHUB
- ioQA™Reporter

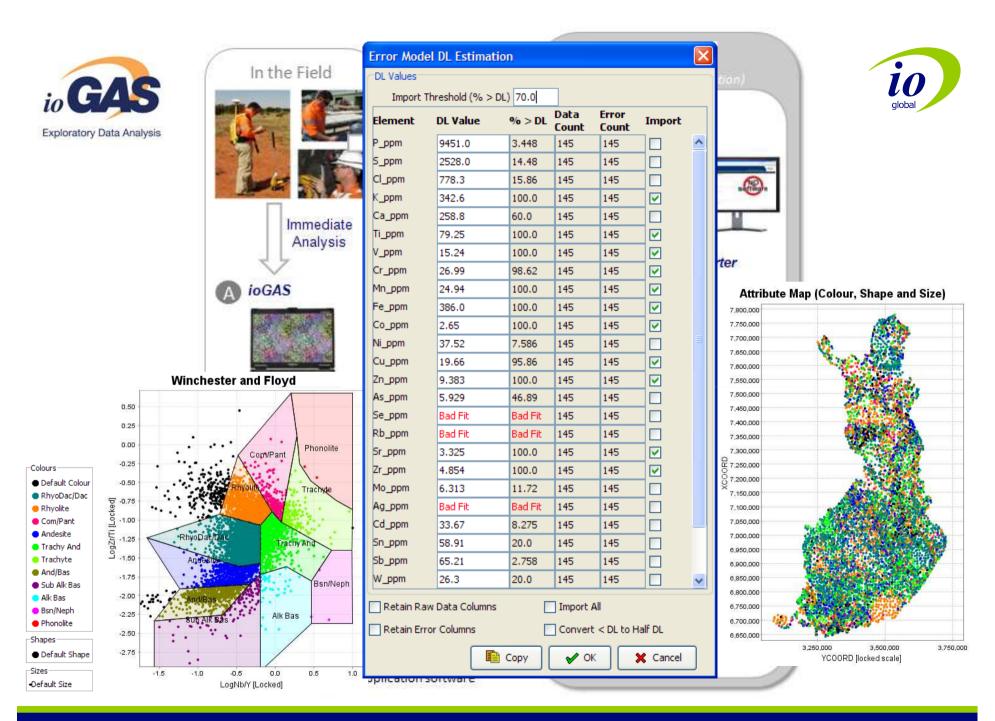


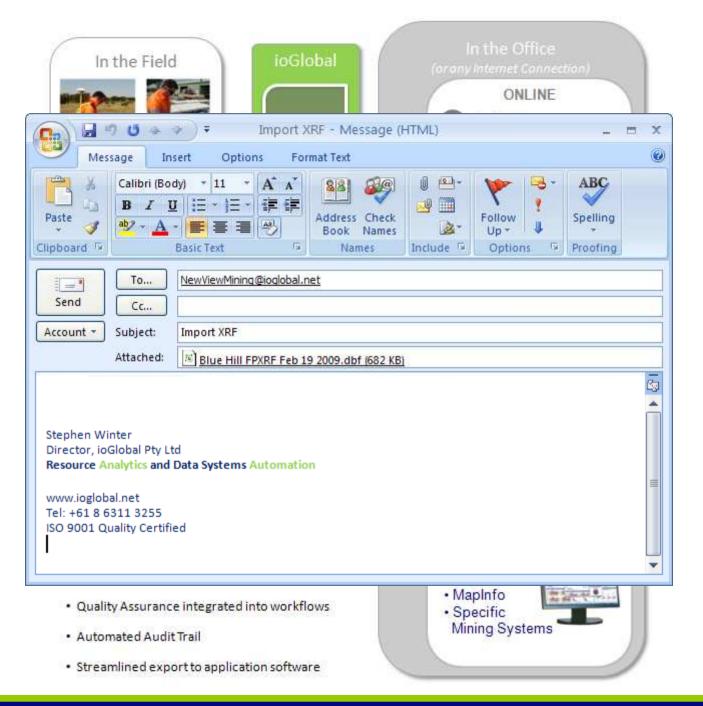


## **QA - Holistic Approach**

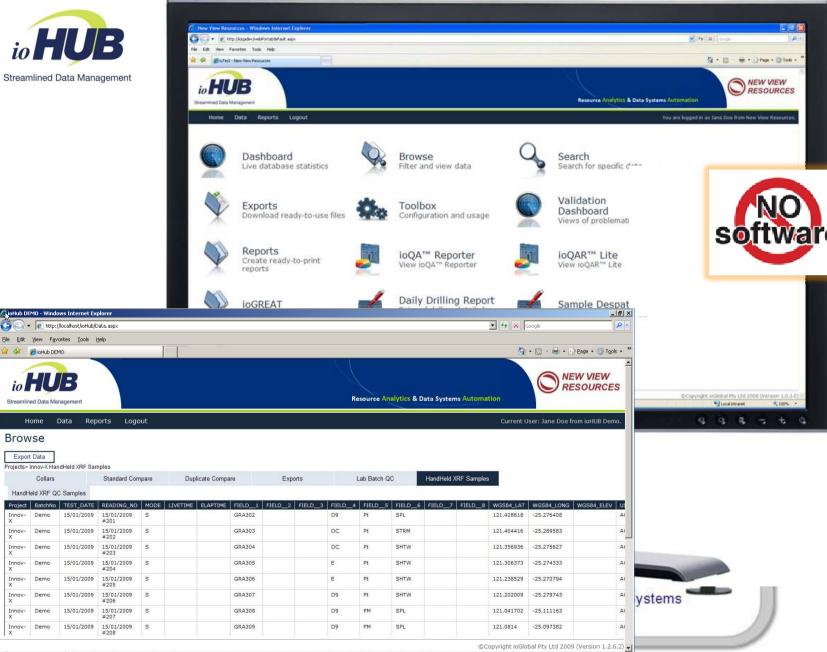












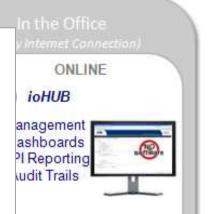
**PXRF Workshop** 

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Innov-



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Lab: Innov-X Systems Element: CU Method: CU_DATA	
Lab: Innov-X Systems Element: MN Method: MN_DATA	
Lab: Innov-X Systems Element: NI Method: NI_DATA	
Lab: Innov-X Systems Element: ZN Method: ZN_DATA	
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Standard: OREAS42P Lab: Innov-X Systems Method: NI DATA Element: NI Over Time Standard Control Chart N=20 700 00r 650 00 600.00 550.00 500.00 400.00 350.00 12 - NI Value - Expected Value ---- +/- 5% Expected Value - +/- 2 Std Dev - +/- 3 Std Dev --- 3 Point Avg Over Time CuSum Bias N=20 40 20 -20 -40 -60 13 12 Analytical Order

- · Quality Assurance integrated into workflows
- · Automated Audit Trail

Field Repeatability Summary Report .....

Summary - NI - NI\_DATA.

Summary - ZN - ZN DATA.

Lab: Innov-X Systems Method: CU\_DATA Method: CU.
Lab: Innov-X Systems Method: MN\_DATA Method: MN.
Lab: Innov-X Systems Method: NI\_DATA Method: NI...
Lab: Innov-X Systems Method: ZN\_DATA Method: ZN.

Standard: OREAS42P Lab: Innov-X Systems Method: CU DATA Element: CU.

Standard: OREAS42P Lab: Innov-X Systems Method: MN\_DATA Element: MN.

Standard: OREAS42P Lab: Innov-X Systems Method: NI\_DATA Element: NI...

Standard: OREAS42P Lab: Innov-X Systems Method: ZN\_DATA Element: ZN... Standard: OREAS43P Lab: Innov-X Systems Method: CU\_DATA Element: CU.

Standard: OREAS43P Lab: Innov-X Systems Method: MN\_DATA Element: MN .

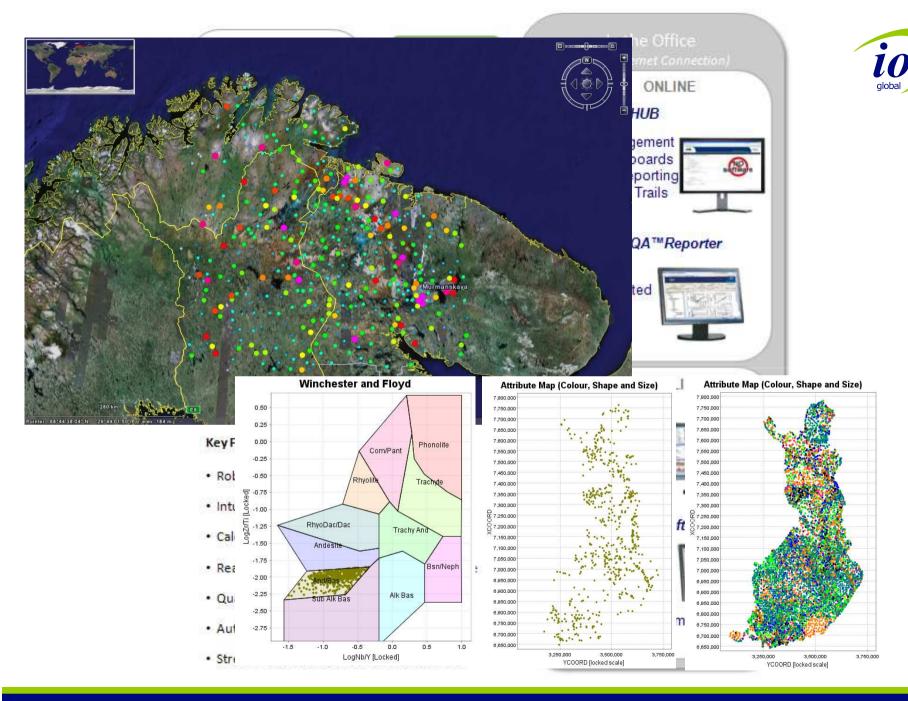
Standard: OREAS43P Lab: Innov-X Systems Method: NI\_DATA Element: NI..... Standard: OREAS43P Lab: Innov-X Systems Method: ZN\_DATA Element: ZN...

Standard: OREAS44P Lab: Innov-X Systems Method: CU\_DATA Element: CU...
Standard: OREAS44P Lab: Innov-X Systems Method: MN\_DATA Element: MN.
Standard: OREAS44P Lab: Innov-X Systems Method: ZN. DATA Element: ZN...

Field Repeatability.....

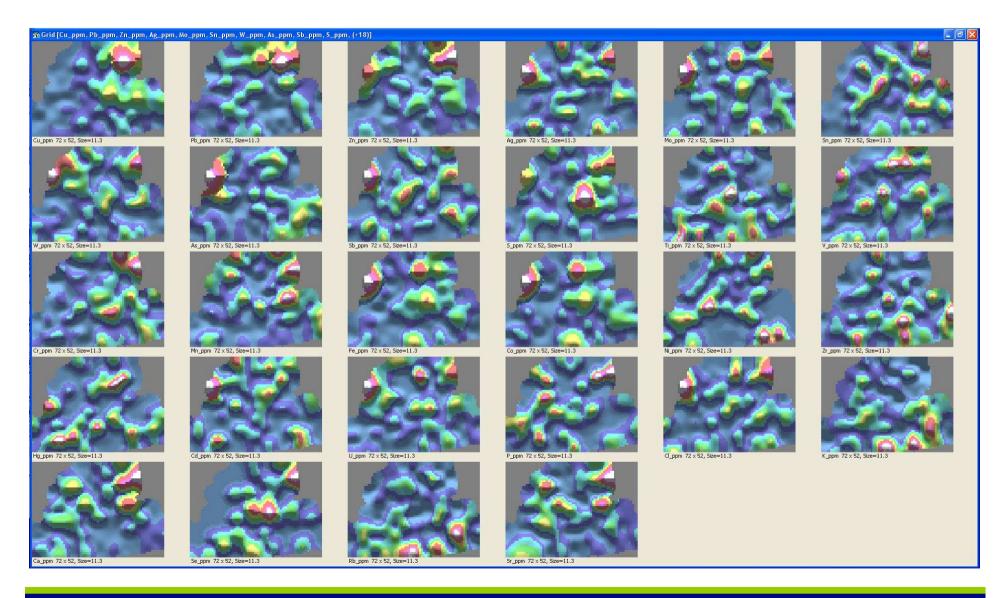
· Streamlined export to application software

-- CuSum(Bias) -- Expected Bias



# In Field Example – Data Imaging







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# Why do we Care?



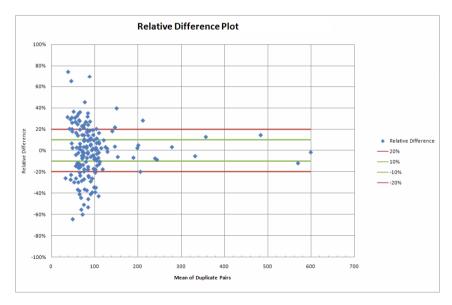
Exploration	Don't miss a target, asses targets properly.
Resources	Data suitable for publicly reported estimates. Geomet implications. Reduce risk
Grade Control	Minimal misclassification.  Geomet – scheduling optimisation.
Plant/Tails/Product	Reconciliation

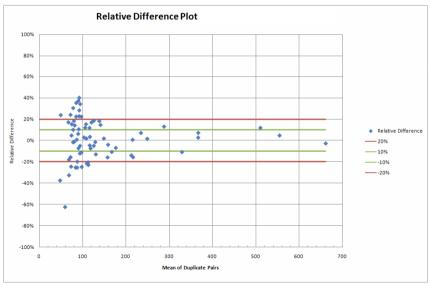


## **Effect of Fraction Size on Precision**

#### 30 second data - Bulk

#### 30 second data -75um





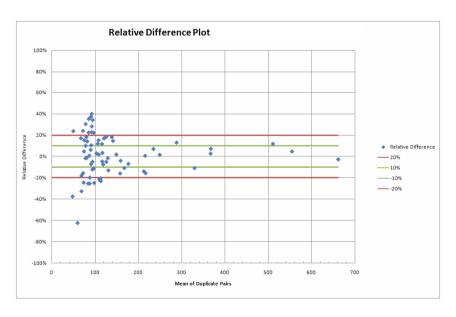
Tighter precision envelope and lower effective detection limit for -75um data

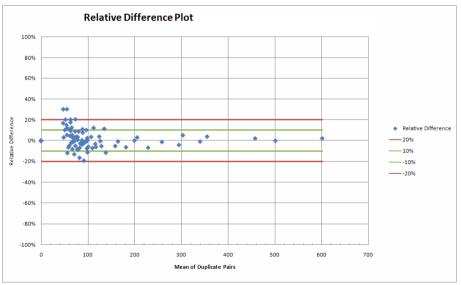


# **Effect of Reading Time on Precision**

#### 30 second data -75um

#### 180 second data -75um





Tighter precision envelope and lower effective detection limit for 180 second data

## Blanks Tests - "Zero" Blank

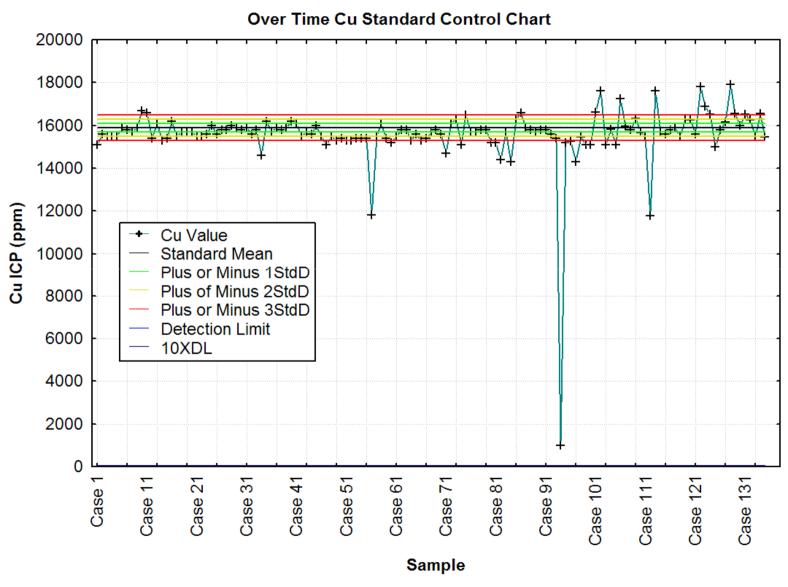


Limit, eg set at multiple of DL or absolute value



### **Example of Analytical Problems 'Over Time' – Cu Analyses**





# Ores45p Cu-ppm

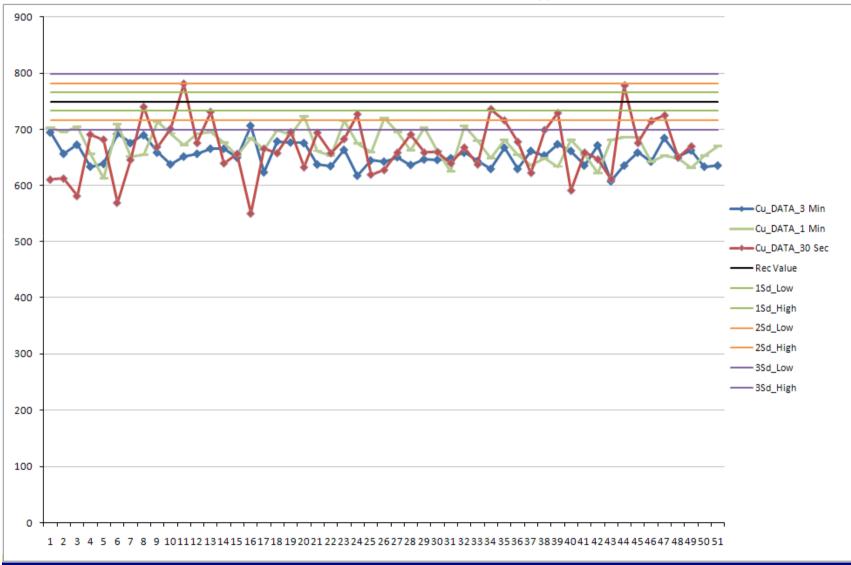
Detection Limits (2sd) and CV

3min – 34ppm, 0.026

1 min – 60ppm, 0.045

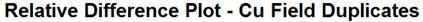
30 sec- 85ppm, 0.064

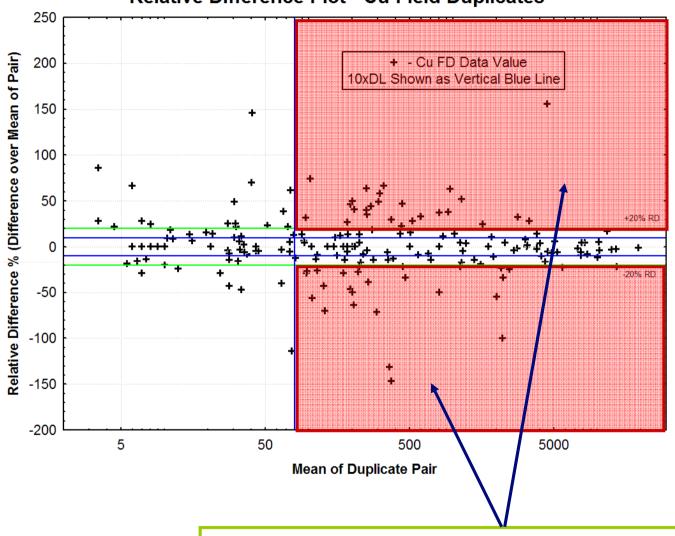




#### **Percent Relative Difference Plots**



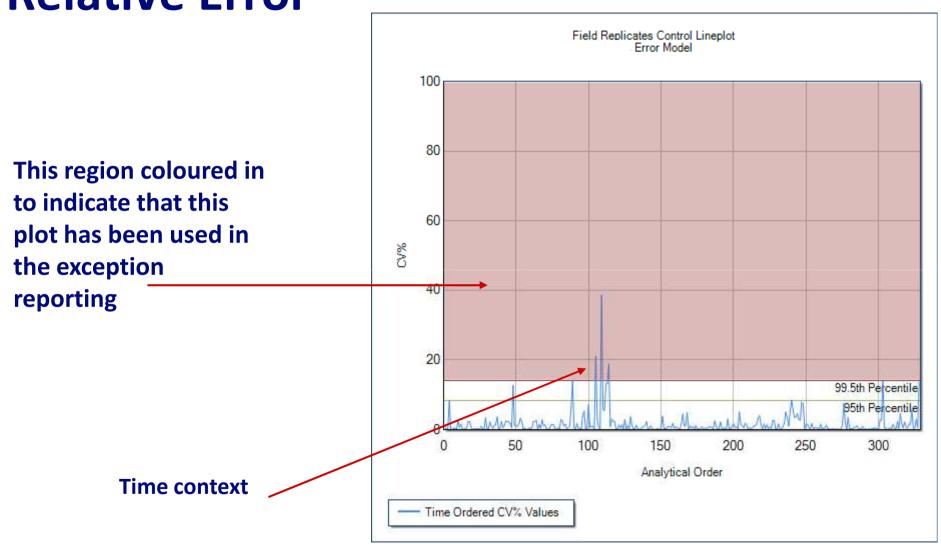




Reported Out of Range Data Come From Here

**Error Model - Test against set Relative Error** 

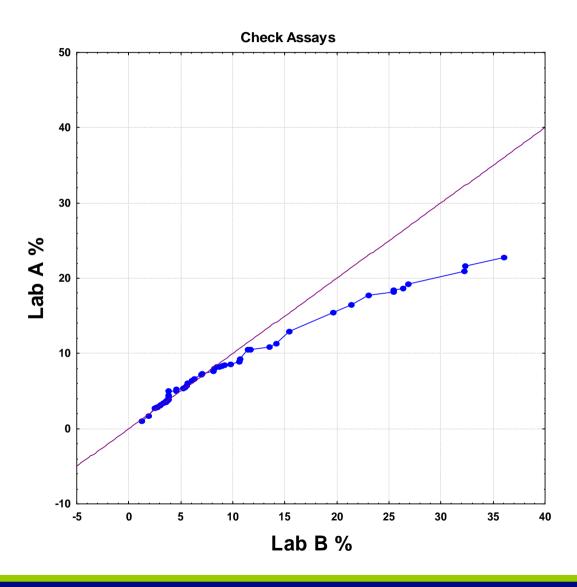




\*Also allows for temporal based variations in precision to be assessed

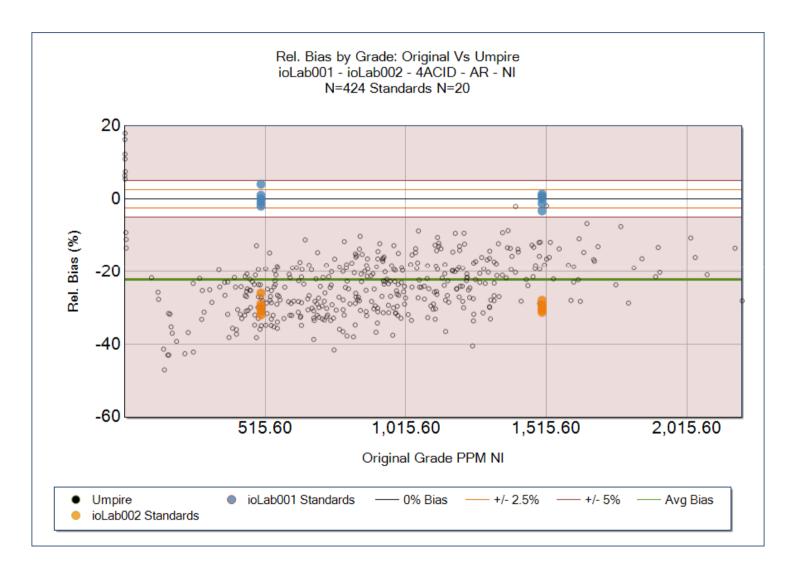
## **Check Assay Example – QQ Plot**





### **Relative Bias**





## **Summary**



- Jorc/43-101 → Transparency and Disclosure
- Collection of Portable XRF requires the same QAQC as other analytical data
- Contamination, Accuracy, Precision, Bias all need to be monitored
- Sample matrix and sampling statistic effects are crucial
- In field use no longer precludes data systems integration and analysis. 'Real time' analysis is a reality
- QC reporting can now be automated